

5th International Conference on Spectroscopic Ellipsometry: ICSE-V 23 - 28 May 2010 Albany NY USA



The 5th International Conference on Spectroscopic Ellipsometry (ICSE-V) continues the tradition of previous Conferences by serving as the premier forum for the international community of scientists and engineers working in the field of ellipsometry and related measurement techniques. ICSE-V covers new advances and developments in science, technology, and applications of spectroscopic ellipsometry including the related optical analysis techniques that commonly exploit polarization. ICSE-V will expand on topics covered at the four previous Conferences by adding new topics such as non-linear optical measurements and further emphasizing related polarization techniques.

ICSE-V will be held at the College of Nanoscale Science and Engineering (CNSE) in Albany, New York. CNSE is home to the \$5 billion Albany NanoTech Complex, the most advanced research enterprise in the academic world. The city of Albany is the historic capital of the state of New York. Located in New York's Tech Valley region, Albany and the surrounding area is known for everything from the unique downtowns of Albany, Schenectady, and Troy, to first-rate horse racing in Saratoga, and now, to a world-class cluster of nanotechnology companies, organizations, and institutions.



Important Dates

October 19, 2009	Website Open for Abstract Submission
January 15, 2010	Abstract Deadline Extended
May 10, 2010	Manuscript Deadline
May 23, 2010	Tutorial and Conference Reception
May 24, 2010	Conference Technical Program Begins

Go to the website to learn more about the exciting program, which this year will also include a day of tutorials on Sunday, May 23rd.

www.icse-v.org

